

# **Multilayer Power Inductor**

#### Features

- 1. High DC bias current due to developed material.
- 2. Low profile and thin thickness.
- 3. Monolithic structure for high reliability.
- 4. Excellent solderability and high heat resistance
- 5. Low DC resistance.
- 6. No cross coupling due to magnetic shield

# Applications

DC-DC converter circuits for mobile phones, DSCs, DVCs, HDDs, PDAs, etc.

## Lead Free Part Numbering

SLM 2520 4R7 M I T

(1) (2) (3) (4) (5) (6)

(1) Series Type

(2) Dimension: Length x Width

(3) Inductance:  $4R7=4.7\mu H$ ;

(4) Inductance Tolerance : M=±20%;N=±30%

(5) Company Code

(6) Packaging: P - Embossed paper tape, 7" reel

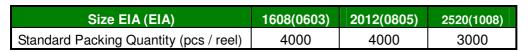
E - Embossed plastic tape, 7" reel

T - Tape & reel

#### Dimensions

Size(EIA)	1608(0603)	2012 (0805)	2520 (1008)
L	1.60±0.150	2.00±0.20	2.50±0.20
W	0.80±0.150	1.25±0.20	2.00±0.20
Т	0.80±0.150	0.90±0.10	0.90±0.10
E	0.30±0.20	0.50±0.30	0.50±0.30

# Package







#### **♦** Test Instruments

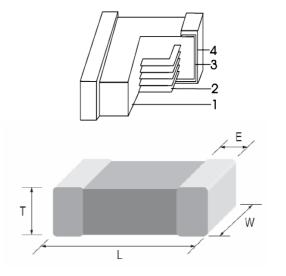
#### **©HP4291B**

RF IMPEDANCE / MATERIAL ANALYZER

#### **©HP4338A/B MILLIOHMMETER**

#### Materials

No.	Homogeneous Material Name	Element name composition
1	Ferrite	Ferrite Powder
2	Inner Coils(Ag)	Ag、Pd
3	Terminal Electrode(Ag)	Ag
4	Electro-Plating (Ni/Sn)	Ni、Sn





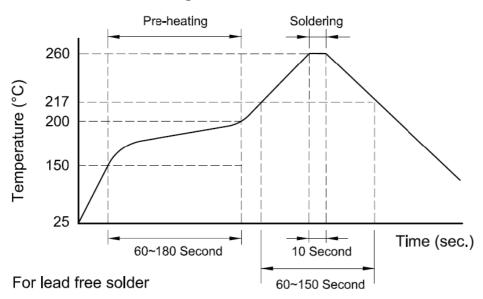
# **◆** Specification

Part Number	Inductance (µH)	Test Freq (MHz)	S.R.F (MHz) Min.	DCR±25% Max. (Ω)	Rated current (mA)	
SLM1608(EIA 0603)						
SLM16081R0MIT	1.0	1	60	0.35	280	
SLM16082R2MIT	2.2	1	50	0.52	250	
SLM16083R3MIT	3.3	1	40	0.75	230	
SLM16084R7MIT	4.7	1	35	0.90	210	
SLM 2012 (EIA 0805)						
SLM20121R0MIT	1.0	1	60	0.15	1000	
SLM20122R2MIT	2.2	1	50	0.20	900	
SLM20123R3MIT	3.3	1	40	0.30	850	
SLM20124R7MIT	4.7	1	35	0.37	750	
SLM2012100MIT	10	1	30	0.55	360	
SLM 2520 (EIA 1008)						
SLM25201R0MIT	1.0	1	60	0.055	1500	
SLM25202R2MIT	2.2	1	40	0.080	1200	
SLM25203R3MIT	3.3	1	35	0.100	1100	
SLM25204R7MIT	4.7	1	30	0.110	1000	
SLM2520100MIT	10	1	20	0.210	550	

#### **♦** General Technical Data

Operating Temperature Range	-55℃~+125℃
Storage Temperature (on board)	-40℃ ~ +85℃
Storage Condition	Less than 40° and 70% RH
Soldering Method	Reflow or Wave Soldering

# **♦** Recommended Soldering conditions





# **SLM Series**

# **♦** Reliability And Test Condition

Test item	Test condition	Criteria	
		1.More than 95 % of terminal electroo	
	1. Solder temperature : 260 ± 5°C	should be covered with new solder	
Resistance to Solder Heat	2. Flux : Rosin	2. No mechanical damage	
	3. DIT time : 10 ± 1 sec	3. Inductance value should be within ± 20 %	
		of the initial value	
	1. Reflow temperature : 245℃ It shall be		
	Soldered on the substrate applying	1. No mechanical damage	
Adhesive Test	direction parallel to the substrate	2. Soldering the products on PCB after the	
	2. Apply force(F): 5 N	pulling test force > 5 N	
	3. Test time: 10 sec		
	1. Temperature : 93 ℃		
	2. Test time: 8 hrs		
Steam Aging Test	3. Solder temperature : 235 ± 5℃	1. More than 95 % of terminal electrode	
	4. Flux : Rosin	should be covered with new solder	
	5. DIT time : 5 ± 1 sec		
	1. Temperature:-40 ~ 85°C For 30 minutes		
	each	1. No mechanical damage	
Temperature Cycle	2. Cycle: 100 cycles	2. Inductance should be within ±20% of the	
	3. Measurement:At ambient temperature 24	initial value	
	hours after test completion		
	1. Temperature: 85 ± 5 °C		
	2. Testing time: 1000 hrs	1. No mechanical damage	
Operational Life	3. Applied current: Full rated current	2. Inductance should be within $\pm$ 20% of the	
	4. Measurement: At ambient temperature 24	initial value	
	hours after test completion		
	1. Temperature: 40°C ± 2°C		
	2. Humidity: 90-95 % RH		
	3. Applied current: Full rated current	1. No mechanical damage	
Biased Humidity	4. Testing time: 1000 hrs	2. Inductance should be within ±20% of the	
	5. Measurement:At ambient temperature 24	initial value	
	hours after test completion		
	At ambient temperature & humidity Testing	SLM product surface temp: below room	
Rated Current	time:5 minutes ( under full rated current )	temperature plus 40°C	
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#### **♦** Characteristics

#### **Inductance vs. Frequency Characteristics**

